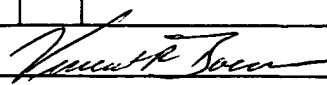


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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249636US2SDIV		SERIAL NO. 10/801,051 New Divisional Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yasufumi TSUMAGARI, et al.			
				FILING DATE Herewith		GROUP Unassigned 2616	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
VKS	AA	6,253,026 B1	26Jun01	Saeki et al.			
VKS	AB	6,263,155 B1	17Jul01	Saeki et al.			
VKS	AC	6,188,835 B1	13Feb01	Grandbois			
VKS	AD	5,838,301	17Nov98	Okamoto et al.			
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VKS	AJ	5,784,528	Jul 1998	Yamane et al.			
VKS	AK	5,771,334	Jun 1998	Yamauchi et al.			
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
VKS	AO	JP 9-245413	19Sep97	JAPAN	x		
VKS	AP	JP 11-96730	9Apr99	JAPAN (with English Abstract) (corresponding to U.S. Patent Nos. 6,253,026 B1 and 6,263,155 B1 (listed above))			X
VKS	AQ	JP 6-103317	15Apr94	JAPAN	x		
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
VKS	AW	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 1999-131475 (with English translation)					
VKS	AX	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-284024 (with English translation)					
VKS	AY	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-284023 (with English translation)					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner 					Date Considered 2/17/06		

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.